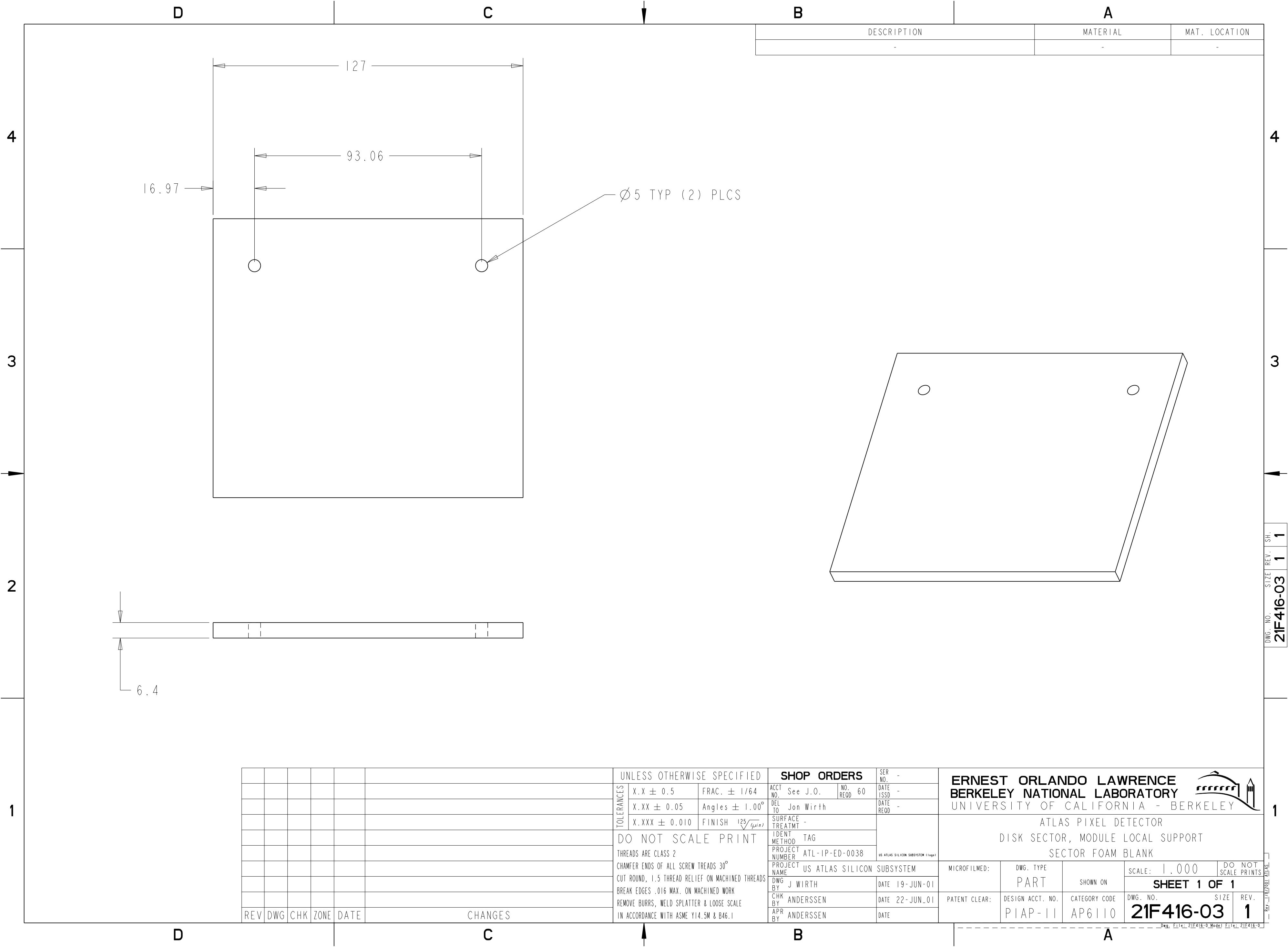
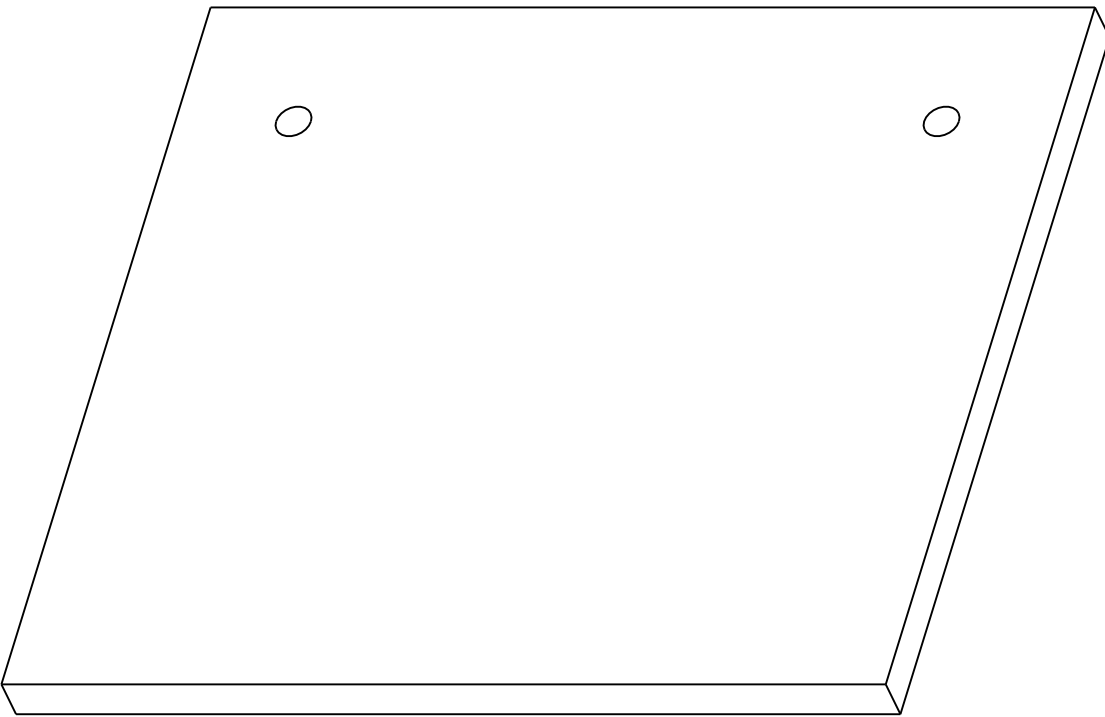




DESCRIPTION	MATERIAL	MAT. LOCATION
-	-	-



							UNLESS OTHERWISE SPECIFIED		SHOP ORDERS		SER NO. -	ERNEST ORLANDO LAWRENCE BERKELEY NATIONAL LABORATORY					
							TOLERANCES	X.X ± 0.5	FRAC. ± 1/64	ACCT NO. See J.O.	NO. REQD 60	DATE ISSD -	ATLAS PIXEL DETECTOR DISK SECTOR, MODULE LOCAL SUPPORT SECTOR FOAM BLANK				
						X.XX ± 0.05		Angles ± 1.00°	DEL TO Jon Wirth	DATE REQD -							
						X.XXX ± 0.010		FINISH $125 \sqrt{(\mu in)}$	SURFACE TREATMT -								
							DO NOT SCALE PRINT			IDENT METHOD TAG			MICROFILMED: DWG. TYPE PART SHOWN ON SCALE: 1.000 DO NOT SCALE PRINTS				
							THREADS ARE CLASS 2			PROJECT NUMBER ATL-IP-ED-0038	US ATLAS SILICON SUBSYSTEM (1page)						
							CHAMFER ENDS OF ALL SCREW TREADS 30°			PROJECT NAME US ATLAS SILICON SUBSYSTEM							
							CUT ROUND, 1.5 THREAD RELIEF ON MACHINED THREADS			DWG BY J WIRTH	DATE 19-JUN-01						
							BREAK EDGES .016 MAX. ON MACHINED WORK			CHK BY ANDERSSSEN	DATE 22-JUN-01	PATENT CLEAR:	DESIGN ACCT. NO.	CATEGORY CODE	DWG. NO.	SIZE	REV.
							REMOVE BURRS, WELD SPLATTER & LOOSE SCALE			APR BY ANDERSSSEN	DATE		PIAP-11	AP6110	21F416-03		1
REV	DWG	CHK	ZONE	DATE	CHANGES												

DWG. NO.	SIZE	REV.	SH.
21F416-03	1	1	1